

March 2009

# FDG410NZ

# Single N-Channel PowerTrench $^{\rm @}$ MOSFET 20 V, 2.2 A, 70 m $_{\Omega}$

### **Features**

- Max  $r_{DS(on)}$  = 70 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 2.2 A
- Max  $r_{DS(on)}$  = 77 m $\Omega$  at  $V_{GS}$  = 2.5 V,  $I_D$  = 2.0 A
- Max  $r_{DS(on)}$  = 87 m $\Omega$  at  $V_{GS}$  = 1.8 V,  $I_D$  = 1.8 A
- Max  $r_{DS(on)}$  = 115 m $\Omega$  at  $V_{GS}$  = 1.5 V,  $I_D$  = 1.5 A
- HBM ESD protection level > 2 kV (Note 3)
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability
- Fast switching speed
- Low gate charge
- RoHS Compliant

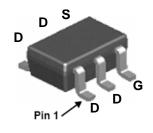


# **General Description**

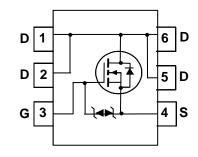
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized use in small switching regulaters, providing an extremely low  $r_{DS(on)}$  and gate charge  $(Q_{\rm g})$  in a small package.

# **Applications**

- DC/DC converter
- Power management
- Load switch



SC70-6



# **MOSFET Maximum Ratings** T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Paramet	er		Ratings	Units
$V_{DS}$	Drain to Source Voltage			20	V
$V_{GS}$	Gate to Source Voltage			±8	V
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	2.2	۸
ID	-Pulsed			6.0	Α
Б	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	0.42	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1b)	0.38	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperatu	ure Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	300	°C/W
Roug	Thermal Resistance, Junction to Ambient	(Note 1b)	333	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
.41	FDG410NZ	SC70-6	7 "	8 mm	3000 units

# **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		17		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 16 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

#### On Characteristics

Symbol

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.4	0.7	1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-3		mV/°C
r <sub>DS(on)</sub> Static Drain to Source On Resistance	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 2.2 A		50	70		
		$V_{GS} = 2.5 \text{ V}, I_D = 2.0 \text{ A}$		56	77	mΩ
	Static Drain to Source On Resistance	$V_{GS} = 1.8 \text{ V}, I_D = 1.8 \text{ A}$		67	87	
	Statio Brain to Godine On Nedistando	$V_{GS} = 1.5 \text{ V}, I_D = 1.5 \text{ A}$		83	115	11132
		$V_{GS} = 4.5 \text{ V}, I_D = 2.2 \text{ A},$ $T_J = 125 ^{\circ}\text{C}$		71	100	
9 <sub>FS</sub>	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_{D} = 2.2 \text{ A}$		11		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 40.V.V 0.V	400	535	pF
Coss	Output Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	70	95	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	45	70	pF
$R_g$	Gate Resistance		2.8		Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			5.3	11	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 2.2 A,		2.3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		18	33	ns
t <sub>f</sub>	Fall Time			2.3	10	ns
$Q_g$	Total Gate Charge	V 45 V V 40 V		5.1	7.2	nC
Q <sub>gs</sub>	Gate to Source Charge	$V_{GS} = 4.5 \text{ V}, V_{DD} = 10 \text{ V},$ $V_{DD} = 2.2 \text{ A}$		0.6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	10 - 2.2 A		1.0		nC

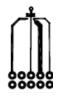
#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain-Source Diode	Maximum Continuous Drain-Source Diode Forward Current			0.35	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 0.35 \text{ A}$ (Note 2)		0.6	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{\rm E} = 2.2  \text{A},  \text{di/dt} = 100  \text{A/us}$		11	20	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_{\rm F} = 2.2  \text{A},  \text{di/dt} = 100  \text{A/} \mu \text{S}$		2.5	10	nC

The R<sub>BJA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>BJC</sub> is guaranteed by design while R<sub>BJA</sub> is determined by the user's board design.



a. 300 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 333 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300 µs, Duty cycle < 2.0%.
3: The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

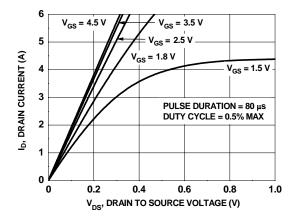
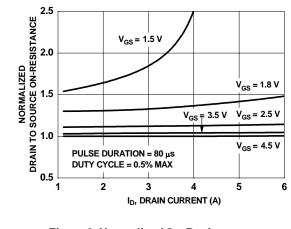


Figure 1. On Region Characteristics



2.5

Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

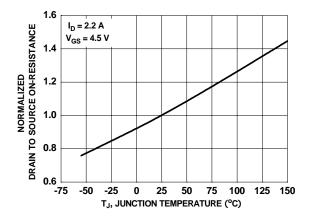


Figure 3. Normalized On Resistance vs Junction Temperature

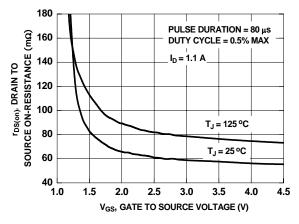


Figure 4. On-Resistance vs Gate to Source Voltage

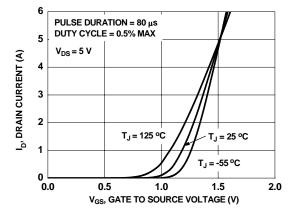


Figure 5. Transfer Characteristics

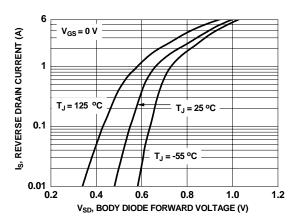


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

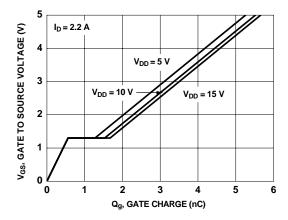


Figure 7. Gate Charge Characteristics

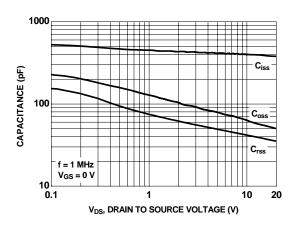


Figure 8. Capacitance vs Drain to Source Voltage

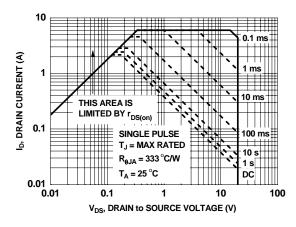


Figure 9. Forward Bias Safe Operating Area

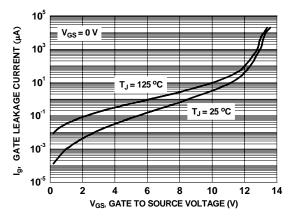


Figure 10. Gate Leakage Current vs Gate to Source Voltage

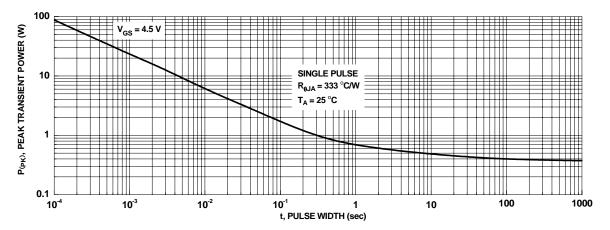


Figure 11. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

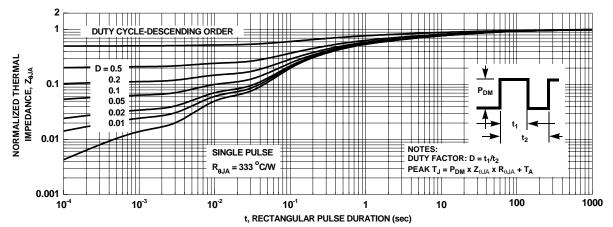
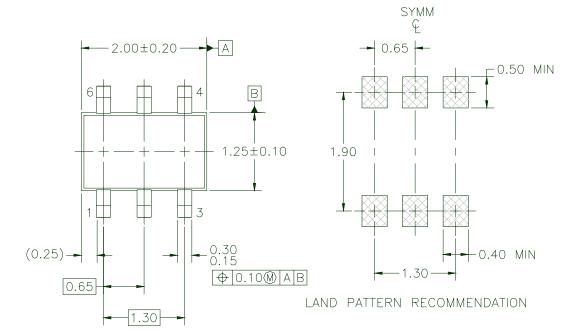
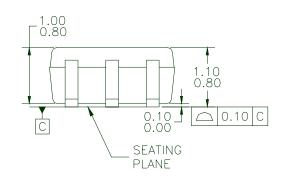
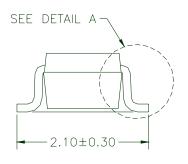


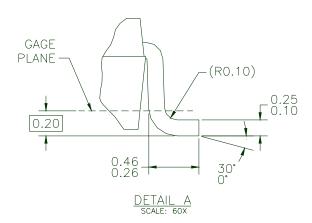
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

# **Dimensional Outline and Pad Layout**









NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE CONFORMS TO EIAJ SC-88, 1996.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH.

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